Supporting Information for

### Surface Oxygen-Injection in Tin Disulfide Nanosheets for Efficient CO2

### **Electroreduction to Formate and Syngas**

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### **S1** Chemicals and Materials

The tin chloride pentahydrate (SnCl<sub>4</sub>·5H<sub>2</sub>O,  $\geq$ 99.0%), thioacetamide (C<sub>2</sub>H<sub>5</sub>NS,  $\geq$ 99.0%), potassium bicarbonate (KHCO<sub>3</sub>,  $\geq$ 99.5%), and ethanol (C<sub>2</sub>H<sub>5</sub>OH,  $\geq$ 99.7%) were all purchased from Sinopharm Chemical Reagent Co. Ltd. (Shanghai, China). Graphite powder (XF011 7782-42-5) and Carbon black (XFI15 7440-44-0) were obtained from XFNANO Materials Tech Co., Ltd. All the chemicals were used without further purification. Ultrapure Millipore water (18.2 MΩ) was used in all experiments.

### **S2** Electrochemical Measurements

Electrochemical measurements were performed in a three-electrode system at an electrochemical station (CHI660E). SnS<sub>2-x</sub>O<sub>x</sub>/CC doesn't require any treatment and can be used as a supporting electrode for electrochemical carbon dioxide reduction directly. Controlled potential electrolysis of CO<sub>2</sub> was conducted in an H-cell (separated by Nafion 115) containing 75 mL of 0.5 M KHCO<sub>3</sub> electrolyte at room temperature and under atmospheric pressure. The platinum network and Ag/AgCl electrode were used as the counter and reference electrodes, respectively. Gas products were analyzed by a thermal conductivity detector (TCD) (for H<sub>2</sub> and CO) and a flame ionization detector (FID) (for alkanes and alkenes). Quantification of the products was performed using standard calibration gases. Liquid products were analyzed by quantitative 1H NMR spectroscopy with water suspension, and using dimethyl sulphoxide (DMSO) as an internal standard.

# **S3** Characterizations

The TEM, HRTEM, HAADF-STEM, and EDX mapping of the SnS<sub>2</sub>/CC, SnS<sub>2-x</sub>O<sub>x</sub>/CC and SnO<sub>2</sub>/CC were carried out on a JEOL ARM-200F field-emission transmission electron microscope operating at 200 kV accelerating voltage. XRD patterns was recorded by using a Philips X'Pert Pro Super diffractometer with Cu-K $\alpha$  radiation ( $\lambda$ =1.54178 Å). XPS measurement was performed on a VG ESCALAB MK II X-ray photoelectron spectrometer with an exciting source of Mg K $\alpha$  = 1253.6 eV.

## **S4 EXAFS Experimental Details**

The Sn *K*-edge (29200 eV) XAFS spectra were performed at BL14W1 station in Shanghai Synchrotron Radiation Facility (SSRF), China. The storage rings of SSRF were operated at 3.5 GeV with the maximum current of 210 mA. During XAFS measurements, we calibrated the position of the absorption edge ( $E_0$ ) using Sn foil. And all the XAFS data were collected during one period of beam time. Each spectrum was measured three times to ensure the repeatability of the data (the positions of  $E_0$  were almost the same during the multiple scans). The position of  $E_0$  is defined as the point corresponding to the maximum value in the derivative curves of the XANES spectra.

# **S5 DFT Calculations**

The calculations were performed within the Density Functional Theory (DFT) framework implanted in Vienna ab initio Simulation Package (VASP)[2]. The interaction between ions and electrons was described in the Projector Augmented Wave (PAW) Method[4]. The electron exchange and correlation energy was described using the generalized gradient approximation-based Perdew–Burke–Erzenhorf (PBE) functional[3]. The models of armchair edges SnS<sub>2</sub> and SnS<sub>2-x</sub>O<sub>x</sub> with a  $1 \times 3 \times 3$  supercell were chosen for the calculation. And all the atoms were fully relaxed during the calculations. A sufficiently large vacuum region of 15 Å was used for all the models to ensure the periodic images were well separated. The Brillouin-zone integrations were carried out using Monkhorst-Pack grids of special points. A gamma-centered (1  $\times 3 \times 1$ ) k-point grid was used for SnS<sub>2</sub> and SnS<sub>2-x</sub>O<sub>x</sub> supercell. To obtain the accurate structure, The plane-wave cutoff energy was set up to 500 eV. The force convergence was set to be <0.02 eV Å<sup>-1</sup>, and the total energy convergence was set to be <10<sup>-5</sup> eV.

The free energy of the adsorbed state was calculated as follows based on the adsorption energy:

$$\Delta G_{HCOO*} = \Delta E_{HCOO*} + \Delta E_{ZPE} + U_{(T)} - T\Delta S$$

where  $\Delta E_{HCOO*}$  is the adsorption energy of hydrogen directly obtained from DFT calculations,  $\Delta E_{ZPE}$  is the zero-point energy, U<sub>(T)</sub> is the heat capacity correction energy, and T is the temperature (T = 298.15 K),  $\Delta S$  is the change in entropy. Herein, the Gibbs energy is corrected by using the VASPKIT code [6].

## **S6 Supplementary Figures and Tables**



Fig. S1 Electron Localization Function (ELF) for pristine SnS<sub>2</sub> slab (a) and SnS<sub>2-x</sub>O<sub>x</sub> slab (b)



**Fig. S2** (a) Typical SEM images of  $SnS_2/CC$ , (b) Typical TEM images of  $SnS_2$  nanosheets, (c) HRTEM image of pristine  $SnS_2$  nanosheets



Fig. S3 (a) Typical SEM images of SnO<sub>2</sub>/CC, (b) Typical TEM images of SnO<sub>2</sub> nanoplatelets



Fig. S4 EDX spectrum of SnS<sub>2-x</sub>O<sub>x</sub> nanosheets



Fig. S5 XRD patterns of pristine SnS<sub>2</sub>/CC, SnS<sub>2-x</sub>O<sub>x</sub>/CC, and SnO<sub>2</sub>/CC



Fig. S6 XPS survey spectra of pristine SnS<sub>2</sub>/CC, SnS<sub>2-x</sub>O<sub>x</sub>/CC, and SnO<sub>2</sub>/CC



**Fig. S7** O 1*s* XPS spectra of SnS<sub>2-x</sub>O<sub>x</sub>/CC and SnO<sub>2</sub>/CC





Fig. S9 O K-edge XAS spectra of SnS<sub>2-x</sub>O<sub>x</sub> and SnO<sub>2</sub>



Fig. S10 S L-edge XAS spectra of  $SnS_2$  and  $SnS_{2-x}O_x$ 



Fig. S11 Normalized XANES spectra of Sn K-edge for Sn foil, SnS<sub>2</sub>, SnS<sub>2-x</sub>O<sub>x</sub>, and SnO<sub>2</sub>

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**Fig. S12** Synchrotron radiation XAFS measurements. The Fourier transforms  $FT(k^3X(k))$  of the extended X-ray absorption fine structure (EXAFS) for Sn K-edge of the pristine SnS<sub>2</sub> (**a**), SnS<sub>2-x</sub>O<sub>x</sub> (**c**), and SnO<sub>2</sub> (**e**). Sn K-edge EXAFS oscillation function  $k^3X(k)$  for the pristine SnS<sub>2</sub> (**b**), SnS<sub>2-x</sub>O<sub>x</sub> (**d**), and SnO<sub>2</sub> (**e**)



Fig. S13 Wavelet transform (WT) of Sn foil, SnS<sub>2</sub>, SnS<sub>2-x</sub>O<sub>x</sub>, and SnO<sub>2</sub>, respectively

Sample	Path	CN	R(Å)	$\sigma^2(10^{-3}\text{\AA}^2)$	$\Delta E_0^{}(eV)$
SnS <sub>2</sub>	Sn-S	6.0	2.55	3.8	2.5
SnO <sub>2-x</sub> O <sub>x</sub>	Sn-S	4.3	2.56	5.0	4.7
	Sn-O	2.1	2.04	3.6	0.3
SnO <sub>2</sub>	Sn-O	6.0	2.09	4.1	-2.7

Table S1 Best fitting EXAFS data for pristine SnS<sub>2</sub>, SnS<sub>2-x</sub>O<sub>x</sub>, and SnO<sub>2</sub>

Note: For SnS<sub>2</sub>: K-range: 2.22-13.20; R-range: 1.47-3.87; amp: 0.85; For SnO<sub>2-x</sub>O<sub>x</sub>: K-range: 2.36-13.61; R-range: 1.20-3.87; amp: 0.85; For Ag: K-range: 2.31-14.01; R-range: 1.09-3.90; amp: 0.90; *CN*; coordination number; R, bonding distance;  $\sigma^2$ , Debye-Waller factor;  $\Delta E_0$ , inner potential shift.



Fig. S14 Linear sweep voltammetry curves (LSV) in the CO<sub>2</sub> saturated 0.5 M KHCO<sub>3</sub> aqueous solution for pristine  $SnS_2/CC$ ,  $SnS_{2-x}O_x/CC$ , and  $SnO_2/CC$ 



**Fig. S15** Plot of concentration with peak-area ratio of HCOOH/DSS. The standard curve showed good linear relation of peak-area ratio for HCOOH/DSS with HCOOH concentration (y= 0.1485x,  $R^2=$  0.9996).



Fig. S16 Charging current density differences plotted against scan rates for pristine  $SnS_2/CC$ ,  $SnS_{2-x}O_x/CC$ 



Fig. S17 CV curves of (a) pristine SnS<sub>2</sub>/CC and SnS<sub>2-x</sub>O<sub>x</sub>/CC with various scan rates



Fig. S18 Tafel plots of pristine SnS<sub>2</sub>/CC and SnS<sub>2-x</sub>O<sub>x</sub>/CC



Fig. S19 Nyquist plots of pristine  $SnS_2/CC$  and  $SnS_{2-x}O_x/CC$ S10 / S12

**Table S2** Structural parameters of  $SnS_{2-x}O_x/CC$  at the Sn *K*-edge extracted from quantitative EXAFS curve-fittings using the ARTEMIS module of IFEFFIT

Sample	Path	CN	R(Å)	$\sigma^{2}(10^{-3}\text{\AA}^{2})$	$\Delta E_0^{} (eV)$
OCV	Sn-S	3.9	2.57	4.3	4.9
	Sn-O	2.5	2.03	4.5	-2.9
-0.4	Sn-S	2.5	2.57	5.3	8.4
	Sn-O	3.6	2.05	3.07	2.5
-0.9	Sn-S	2.5	2.58	7.8	9.3
	Sn-O	4.2	2.05	4.1	5.3
After reaction	Sn-S	2.5	2.58	7.5	9.6
	Sn-O	3.6	2.05	3.0	2.7



**Fig. S20** (a) Least-squares curve-fitting analysis of operando EXAFS spectra at the Sn K-edge (b) Corresponding  $\text{Re}(k^2\chi(k))$  oscillations



Fig. S21 XRD patterns of SnS<sub>2-x</sub>O<sub>x</sub>/CC before and after reaction



Fig. S22 Optimized adsorption configurations of HCOO\* intermediates on the surface of the pristine  $SnS_2$  slab (a) and  $SnS_{2-x}O_x$  slab (b)



**Fig. S23** Electron density difference plot of the HCOO\* intermediate adsorption structure for pristine  $SnS_2$  slab (**a**) and  $SnS_{2-x}O_x$  slab (**b**). Yellow contours indicate electron accumulation and light green contours denote electron deletion.